## Notice of References Cited

ı	Application/Control No.	Applicant(s)/Pater	Patent Under		
	10/718,376	Reexamination FICKLE ET AL.			
	Examiner	Art Unit			
	SON P. HUYNH	2424	Page 1 of 1		

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0143565	10-2002	Headings et al.	705/1
*	В	US-7,024,681	04-2006	Fransman et al.	725/115
*	С	US-2003/0028896	02-2003	Swart et al.	725/127
*	D	US-6,014,644	01-2000	Erickson, Ranel E.	705/37
*	Е	US-2002/0108121	08-2002	Alao et al.	725/110
*	F	US-2002/0083148	06-2002	Shaw et al.	709/214
*	G	US-7,434,242	10-2008	Goode, Christopher W. B.	725/9
*	Н	US-2002/0013947	01-2002	Russell et al.	725/90
*	Т	US-2004/0205116	10-2004	Pulier et al.	709/203
*	J	US-6,980,972	12-2005	Allibhoy et al.	705/51
*	к	US-5,923,361	07-1999	Sutton, Jr., Garnett Graham	725/93
	L	US-			
	м	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

 NON-PATENT DOCUMENTS					
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	v				
	w				
	x				

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.